

<b>Notice of References Cited</b>	Application/Control No. 10/804,236		Applicant(s)/Patent Under Reexamination KIM ET AL.	
	Examiner Joseph L. Perrin, Ph.D.		Art Unit 1746	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-7,096,695	08-2006	No et al.	68/58
*	C	US-6,889,399	05-2005	Steiner et al.	8/159
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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	O	✓ DE 537758	11-1931	Germany	MOOK	
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	U	✓ Electronic translation of JP 09-215894.
	V	✓ Electronic translation of DE 537758.
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	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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